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(12) **United States Design Patent**
Nakahara et al.

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(54) **X-RAY PRODUCTION APPARATUS FOR INSPECTION TOUR**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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Mar. 12, 2008 (JP) 2008-006084

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.** **D24/158**

(58) **Field of Classification Search** D24/158-161,
D24/183, 186; 378/4, 15, 17, 19, 20, 21-27,
378/38-40, 102, 146, 195, 197, 198; 600/409,
600/410, 425, 476

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for an X-ray production apparatus for inspection tour, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of an X-ray production apparatus for inspection tour showing the new design;

FIG. 2 is a front view of FIG. 1;

FIG. 3 is a rear view of FIG. 1;

FIG. 4 is a left side view of FIG. 1;

FIG. 5 is a right side view of FIG. 1;

FIG. 6 is a top view of FIG. 1;

FIG. 7 is a bottom view of FIG. 1;

FIG. 8 is another perspective reference view of FIG. 1 showing the new design in use;

FIG. 9 is a perspective view of an X-ray production apparatus for inspection tour showing another embodiment of the new design;

FIG. 10 is a front view of FIG. 9;

FIG. 11 is a rear view of FIG. 9;

FIG. 12 is a left side view of FIG. 9;

FIG. 13 is a right side view of FIG. 9;

FIG. 14 is a top view of FIG. 9;

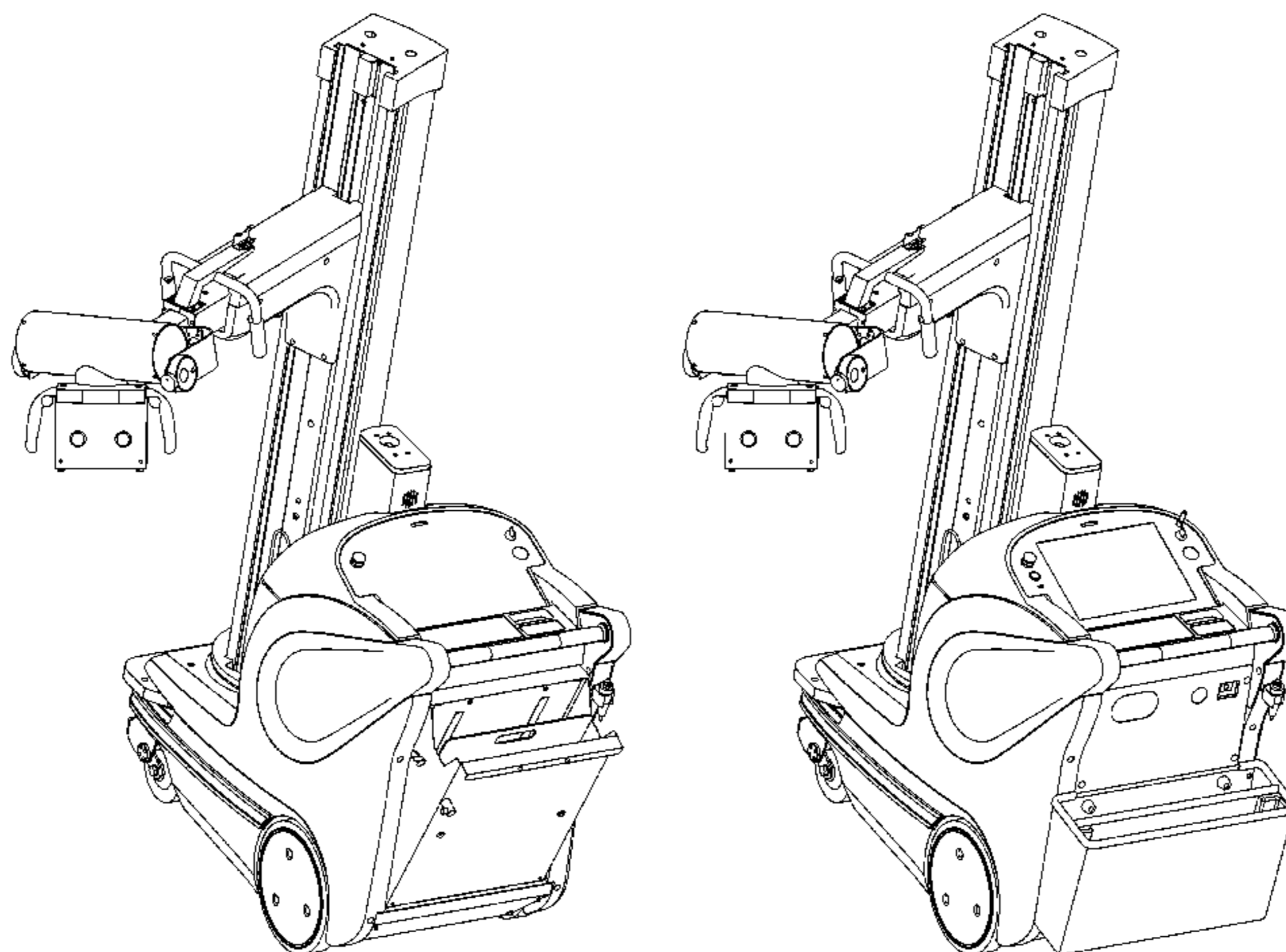
FIG. 15 is a bottom view of FIG. 9;

FIG. 16 is another perspective reference view of FIG. 9 showing the new design in use; and,

FIG. 17 is a partially enlarged view of FIG. 16.

The portions of the X-ray production apparatus for inspection tour in broken lines in FIGS. 6, 7, 14 and 15 form no part of the claimed design.

1 Claim, 17 Drawing Sheets



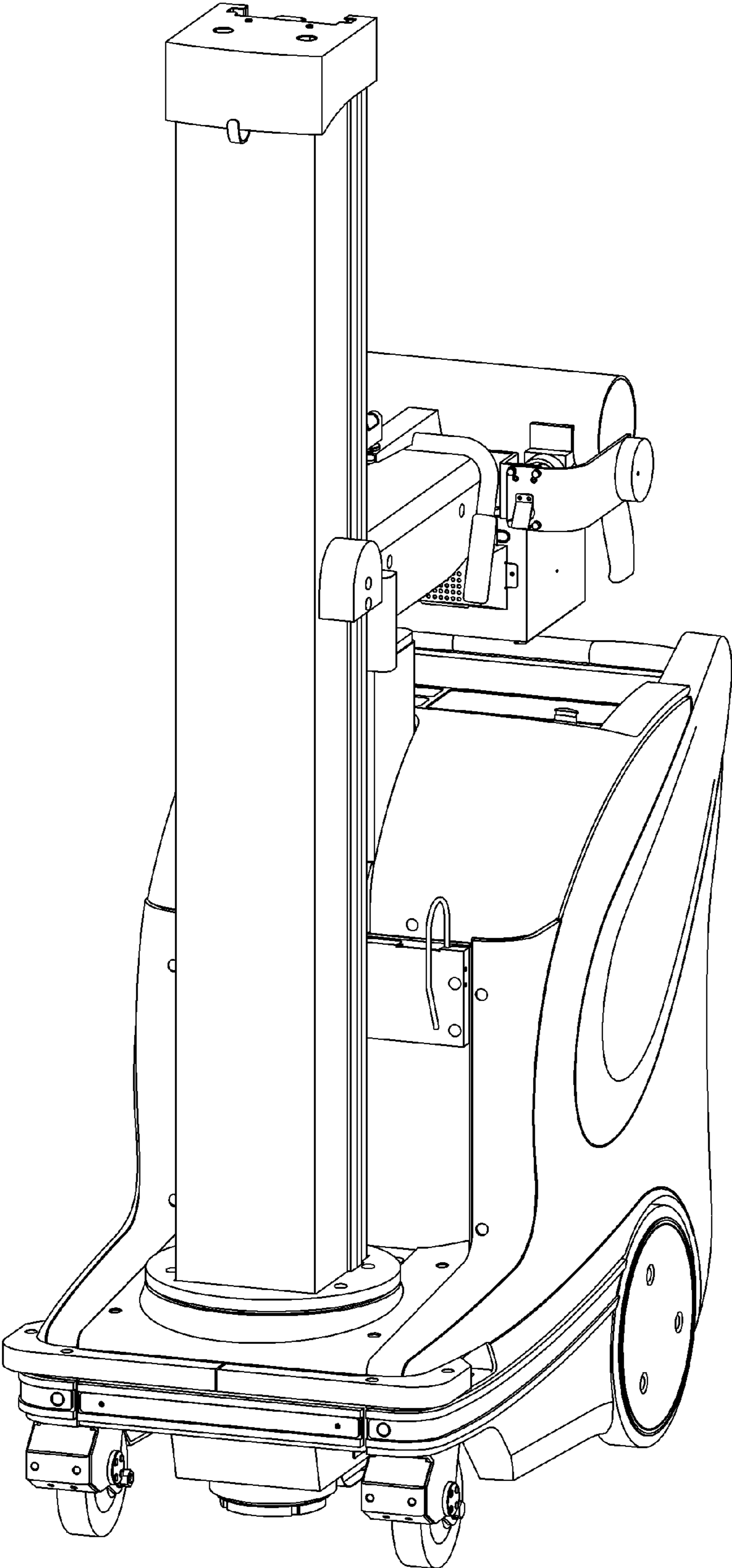


FIG. 1

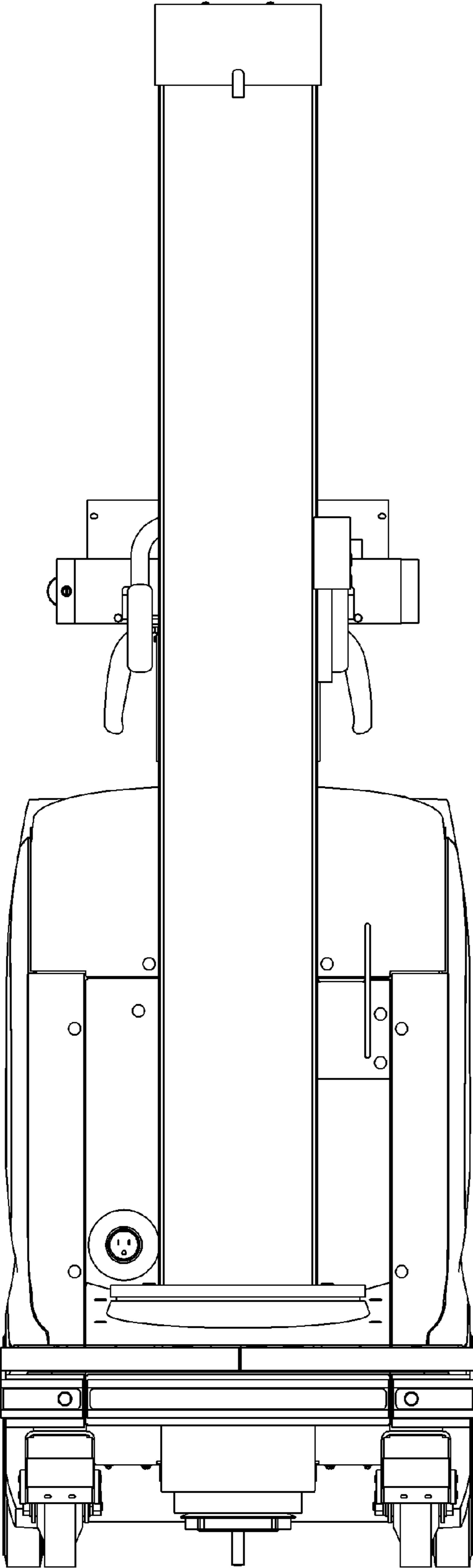


FIG. 2

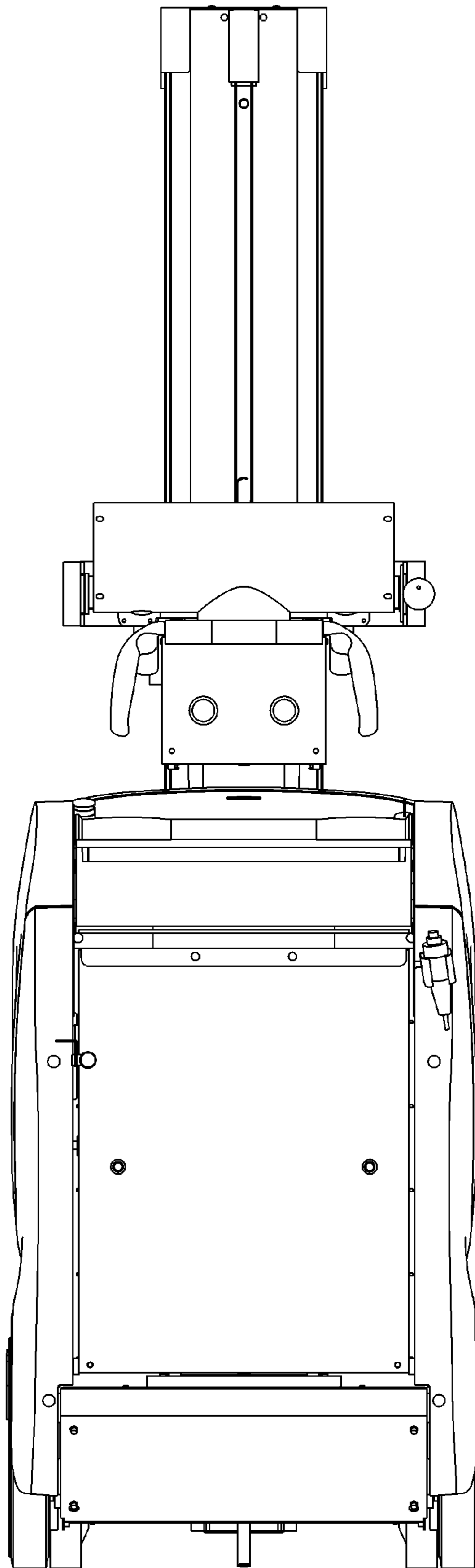


FIG. 3

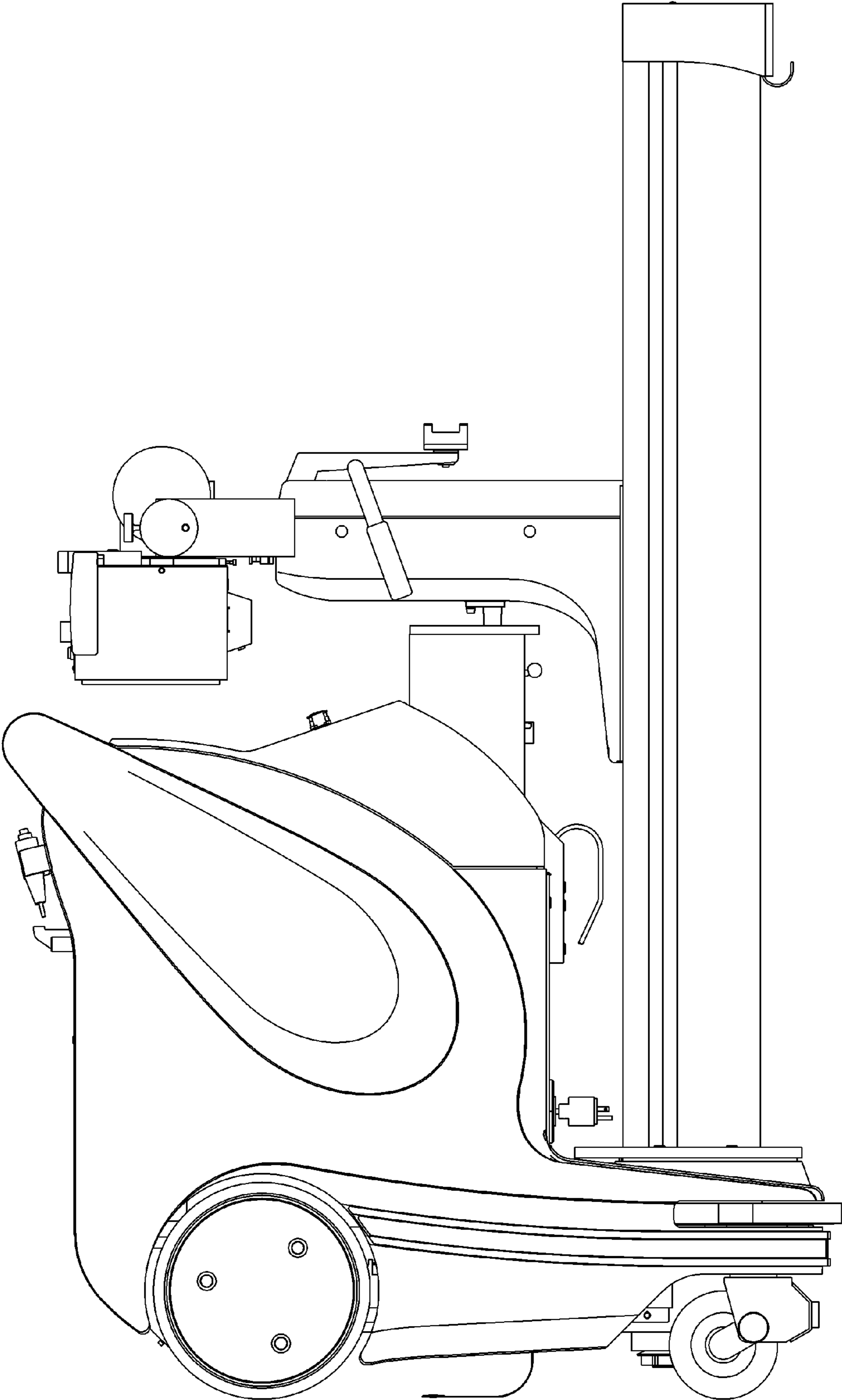


FIG. 4

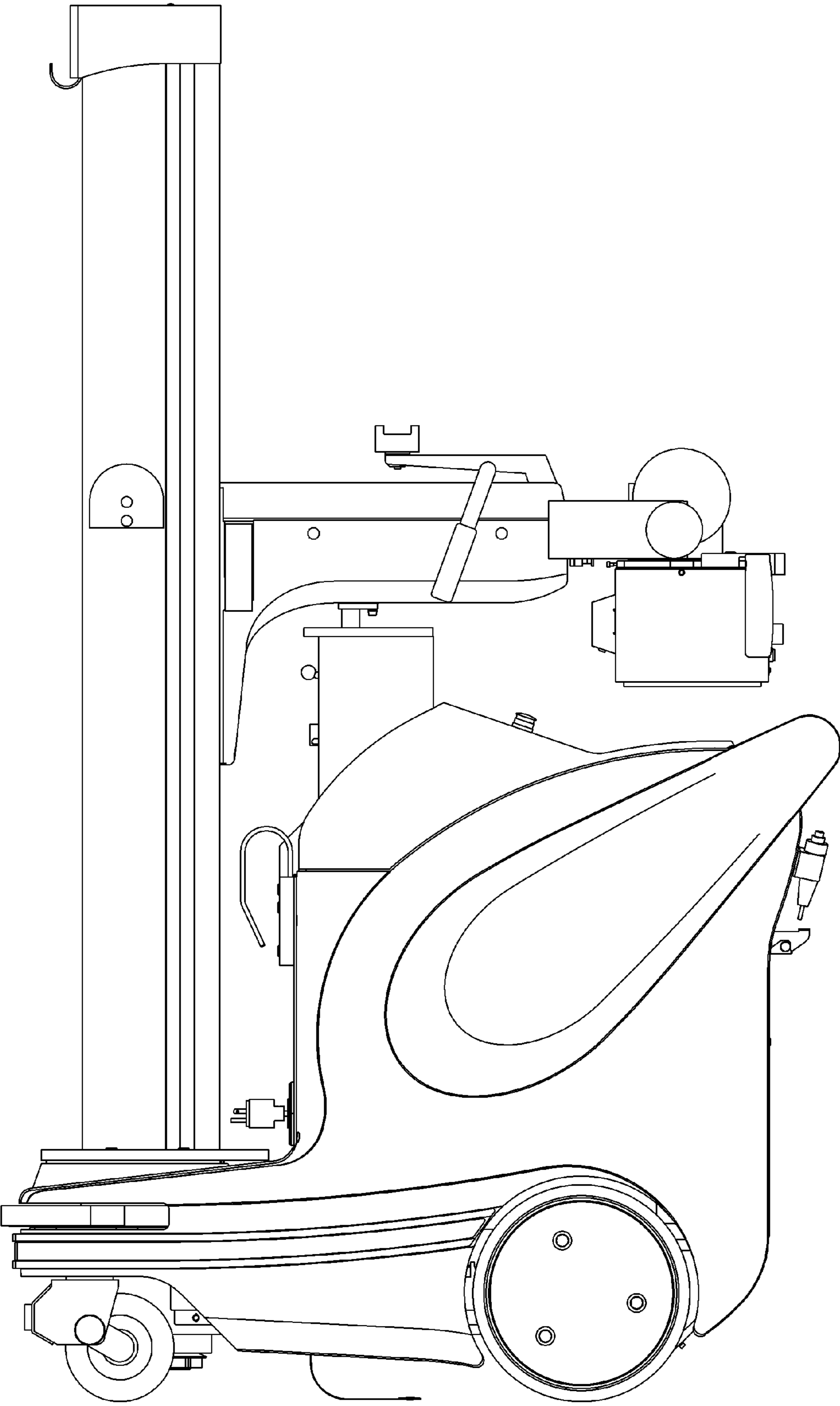


FIG. 5

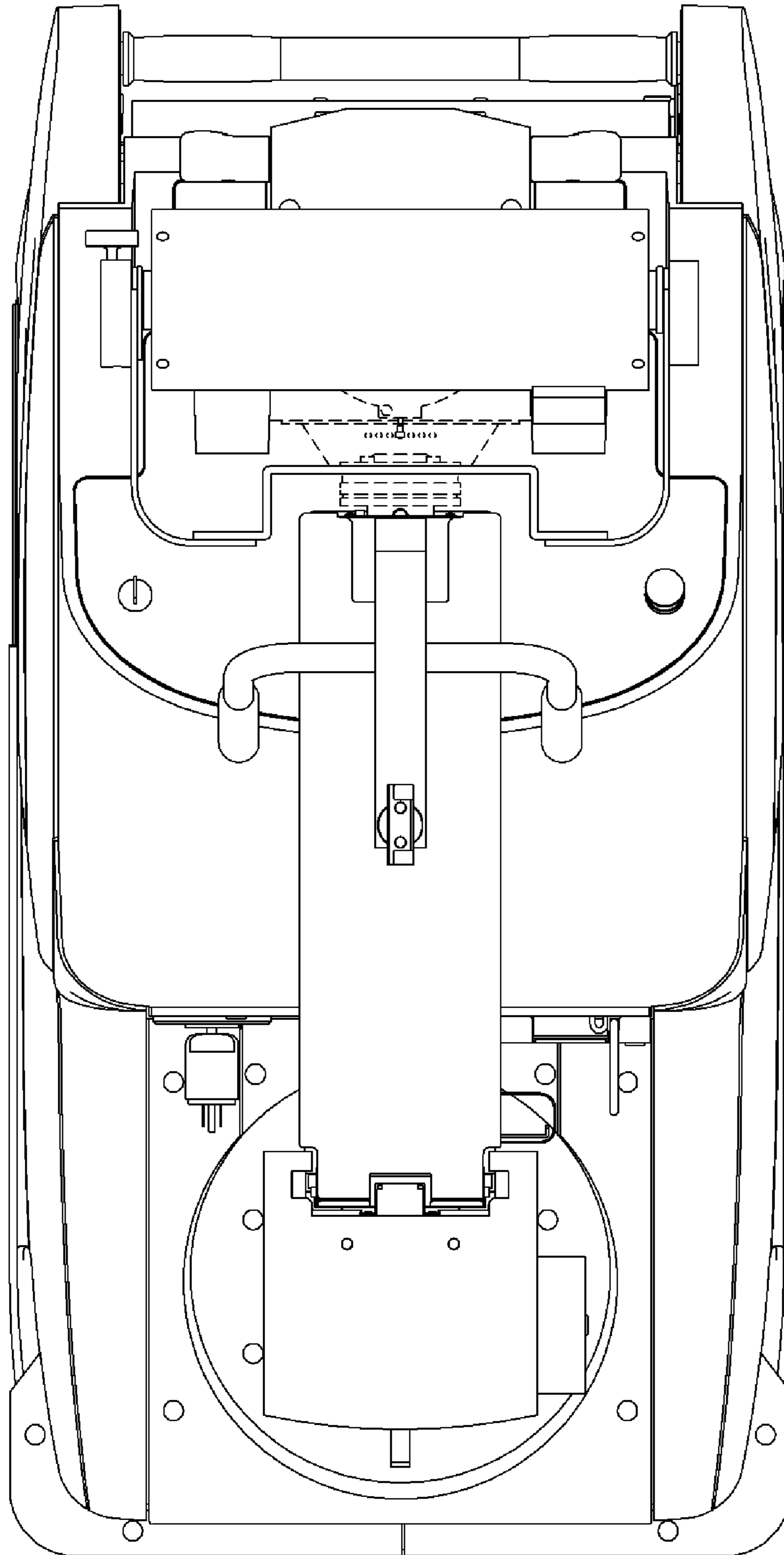


FIG. 6

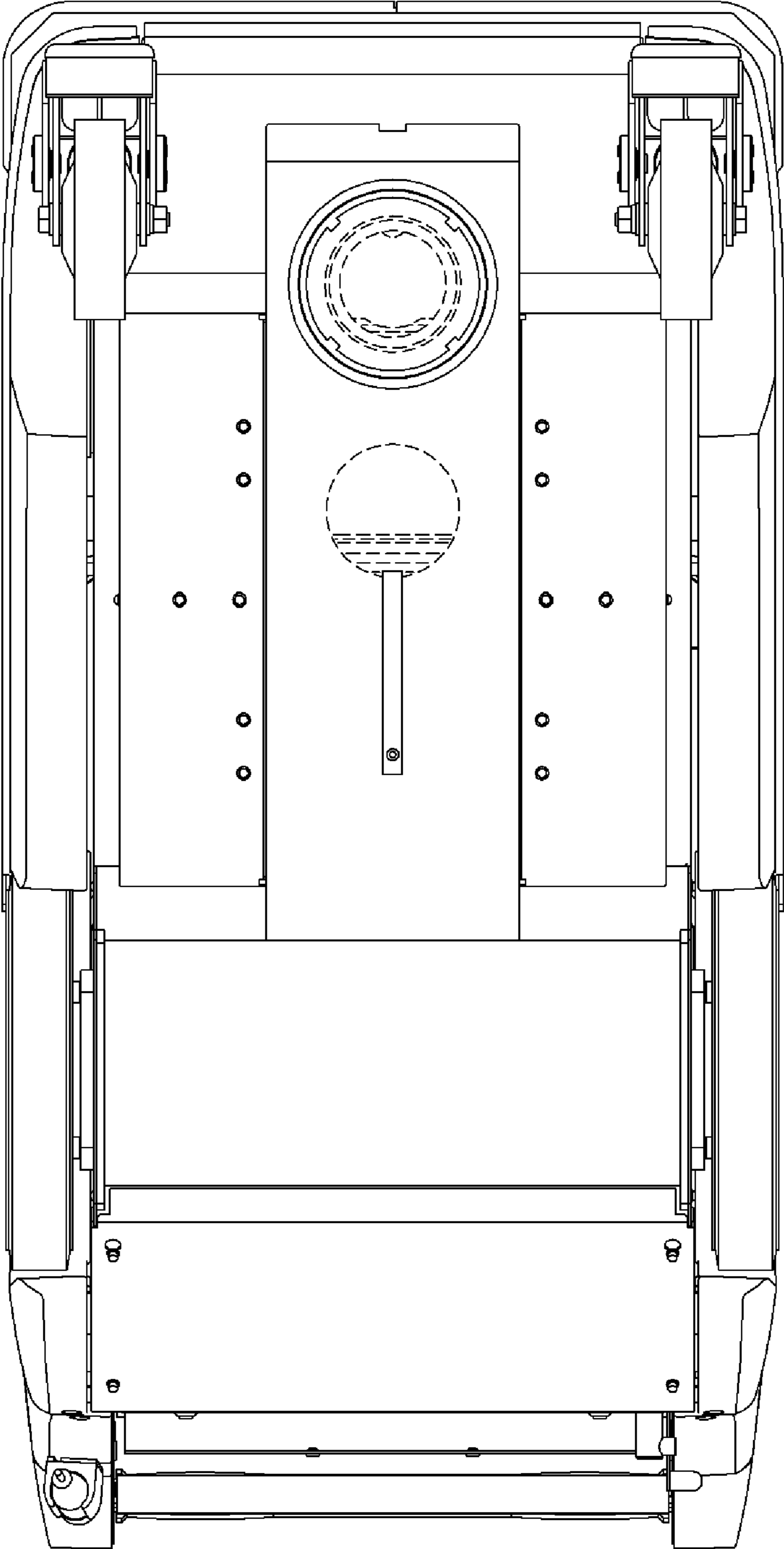


FIG. 7

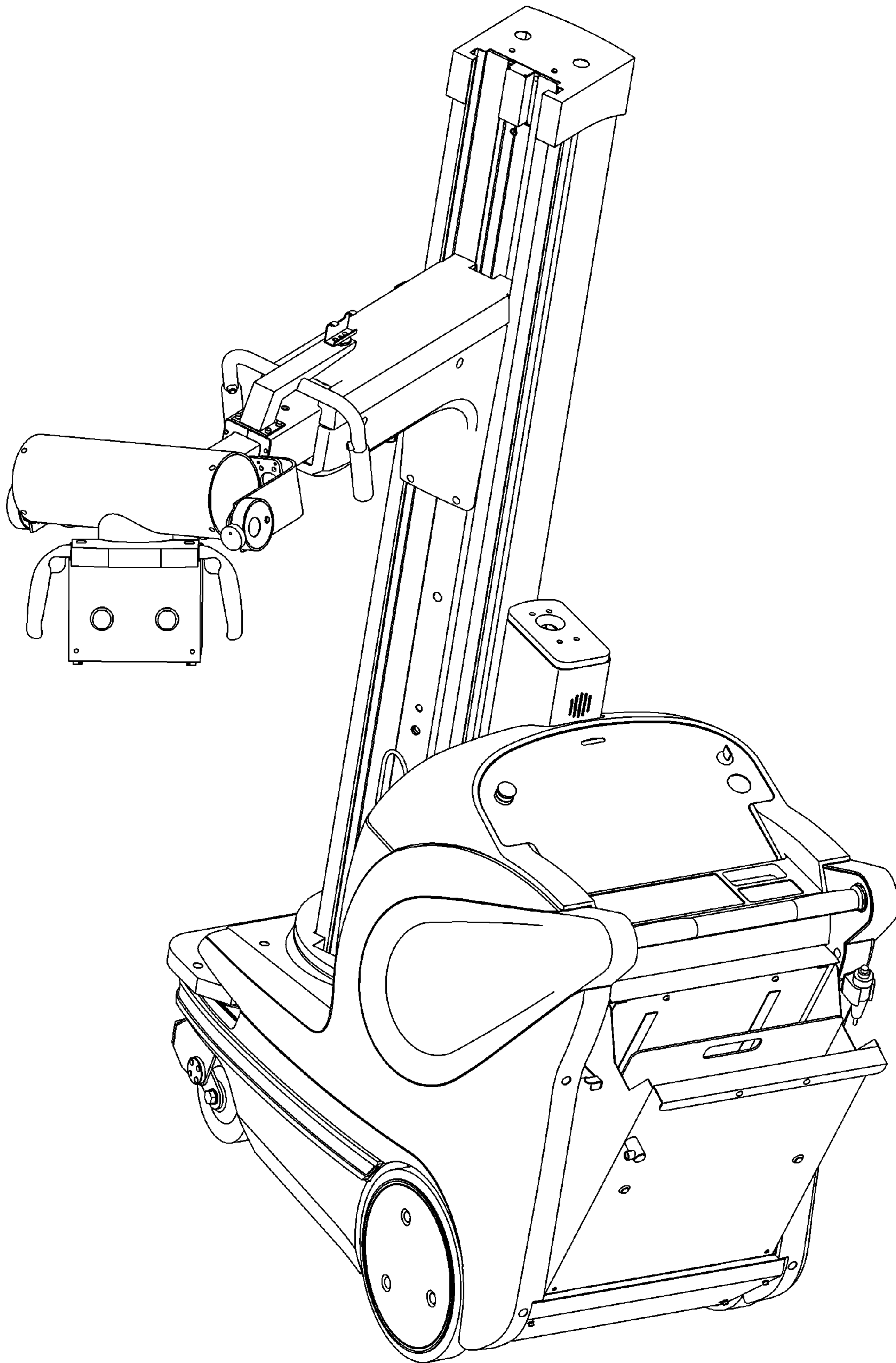


FIG. 8

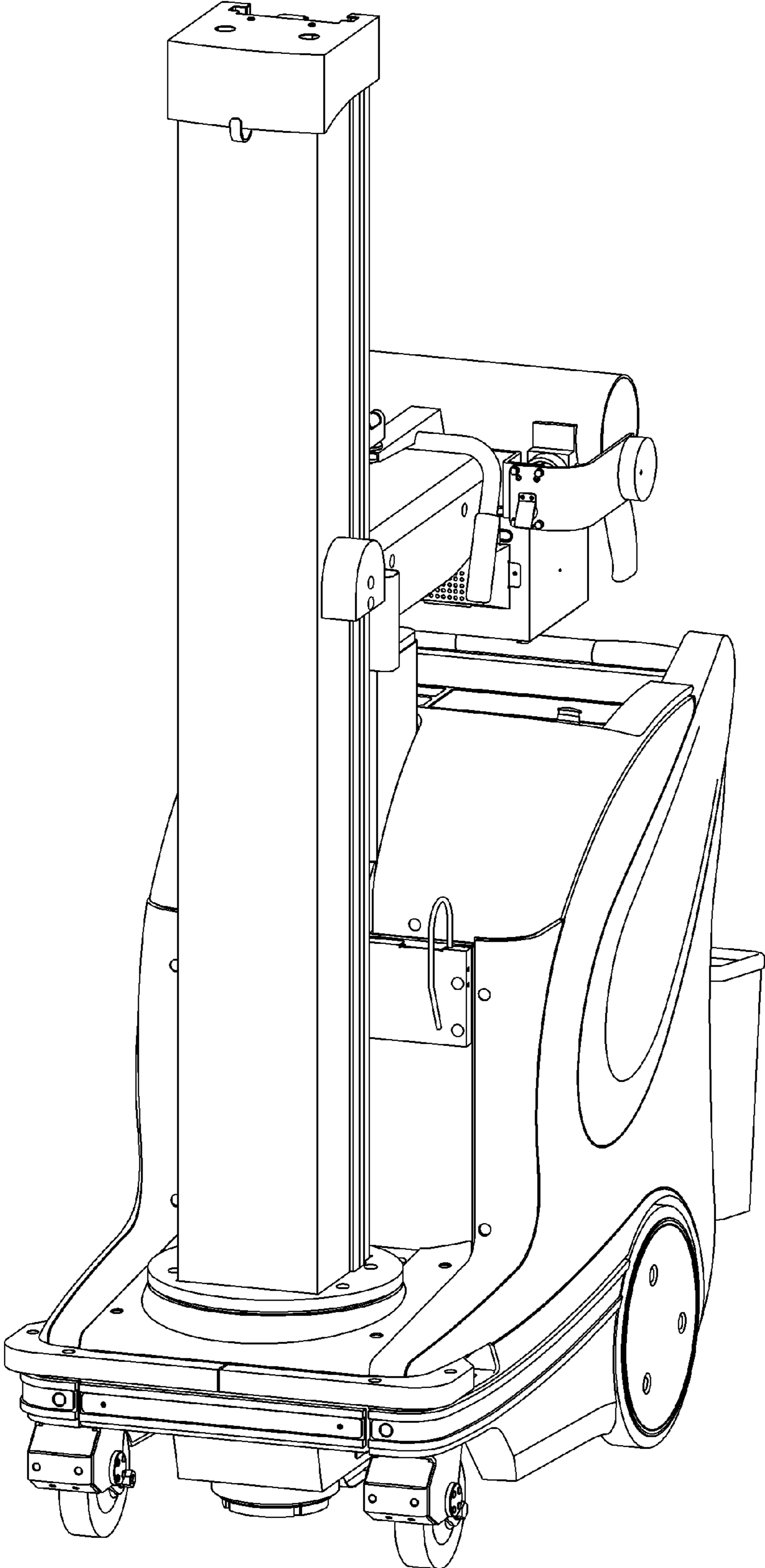


FIG. 9

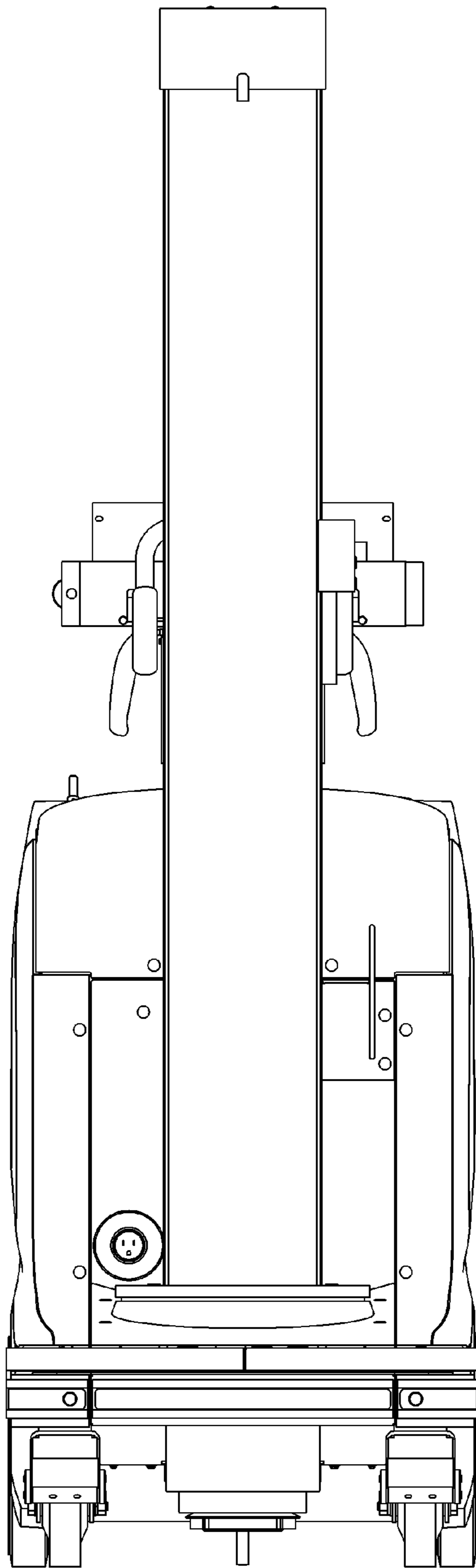


FIG. 10

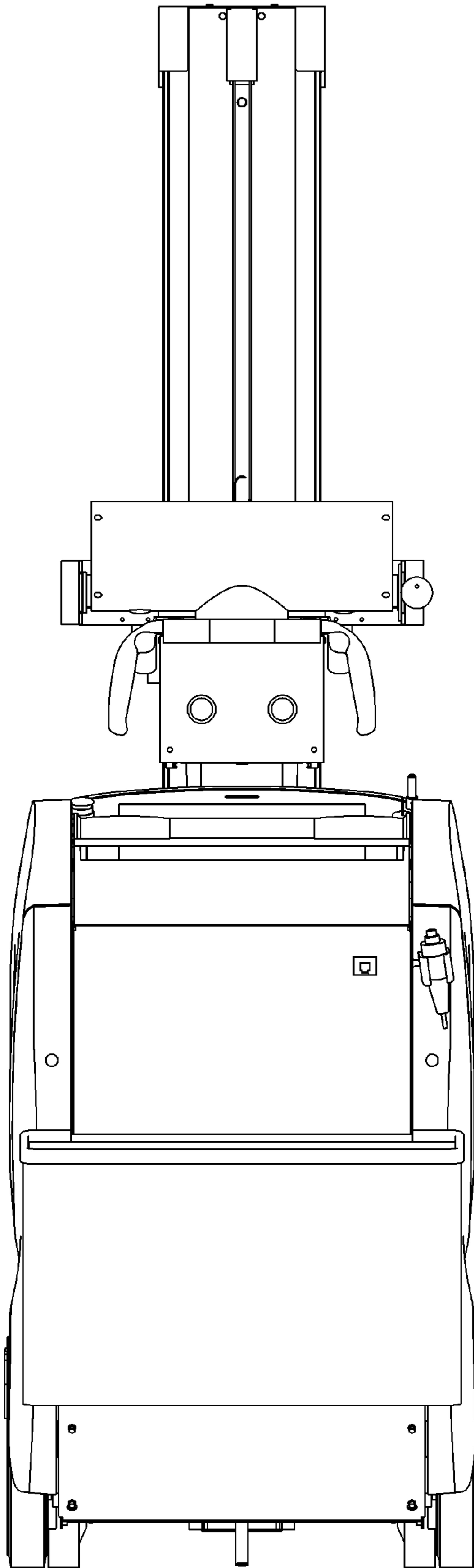


FIG. 11

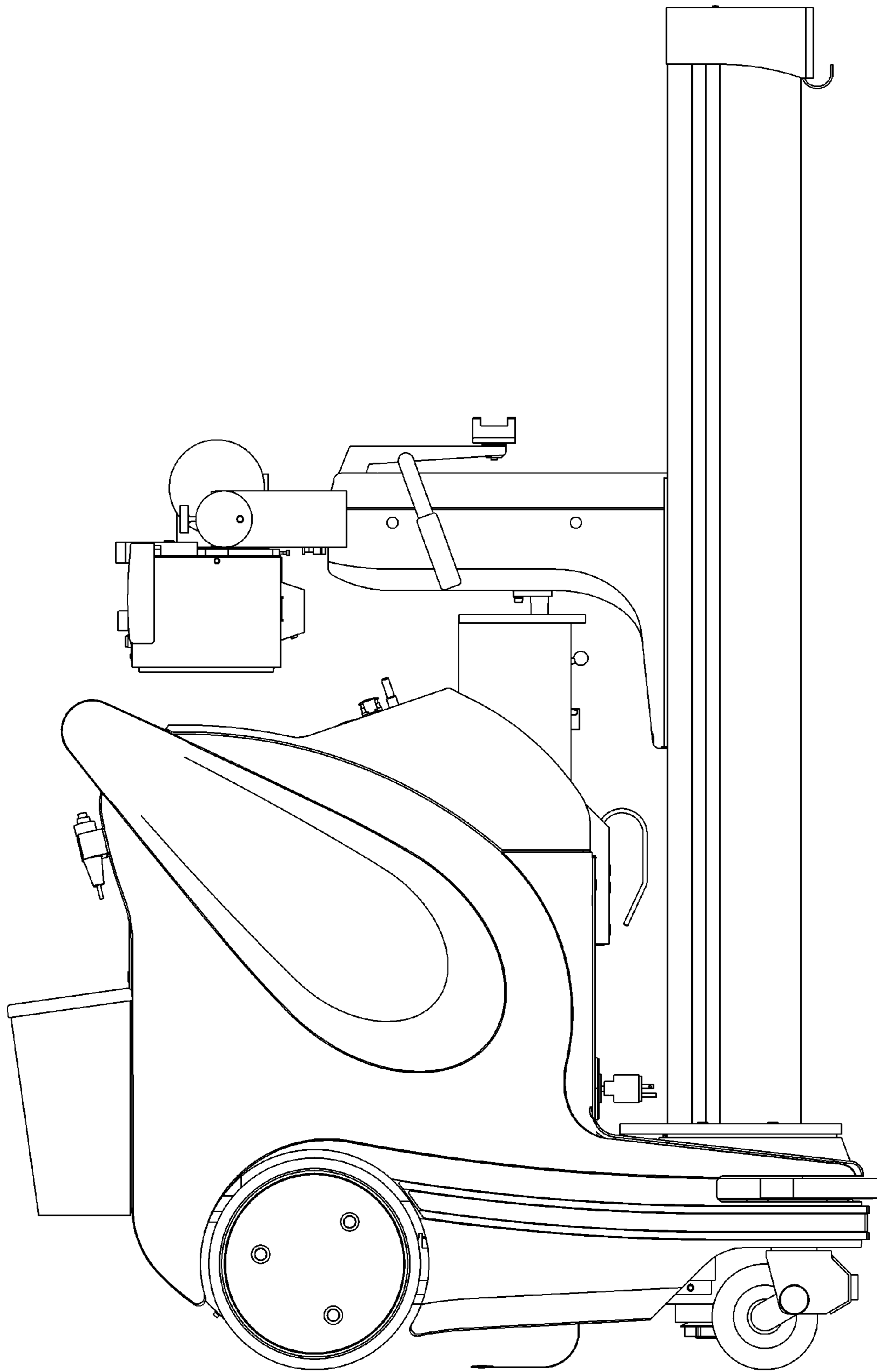


FIG. 12

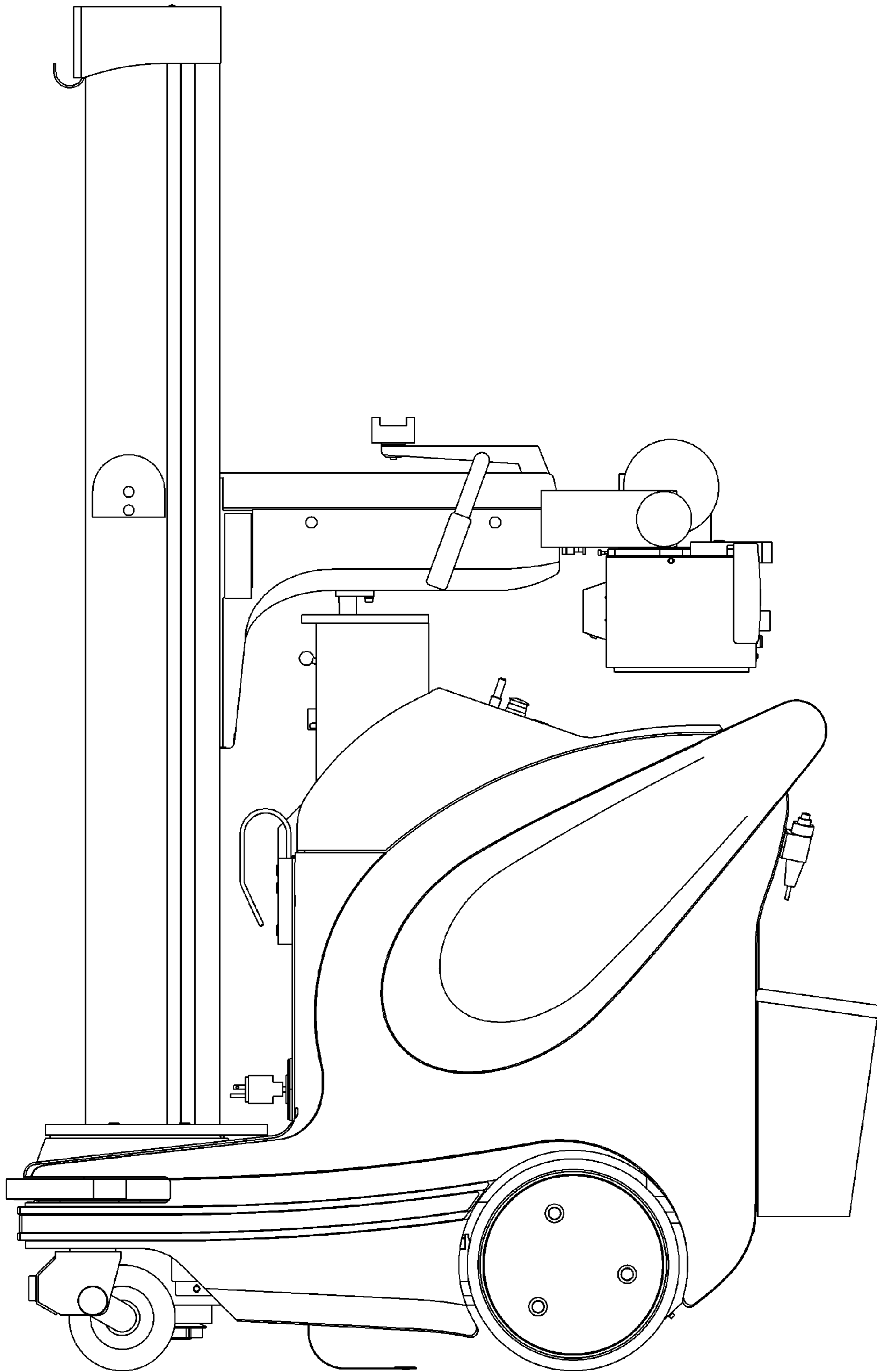


FIG. 13

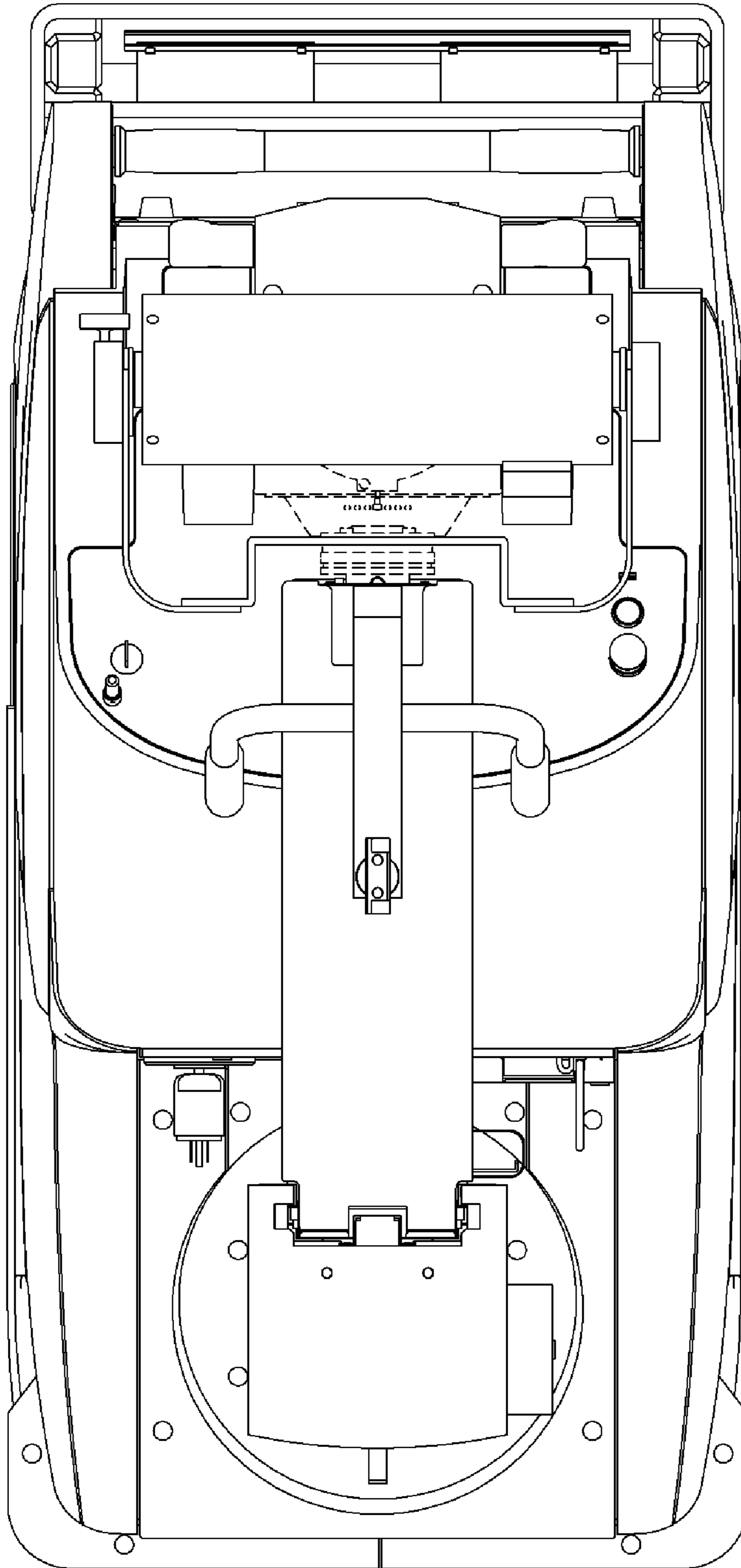


FIG. 14

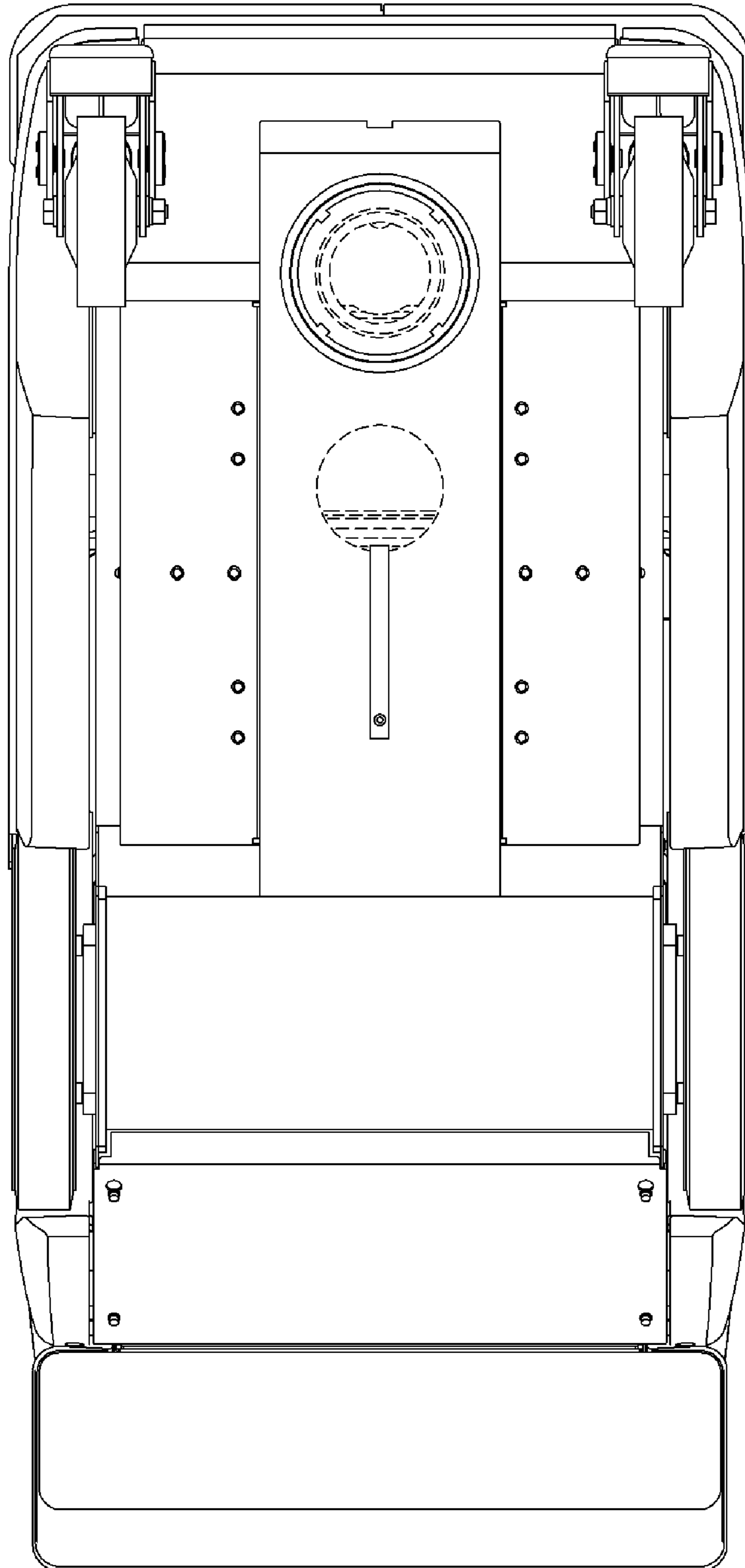


FIG. 15

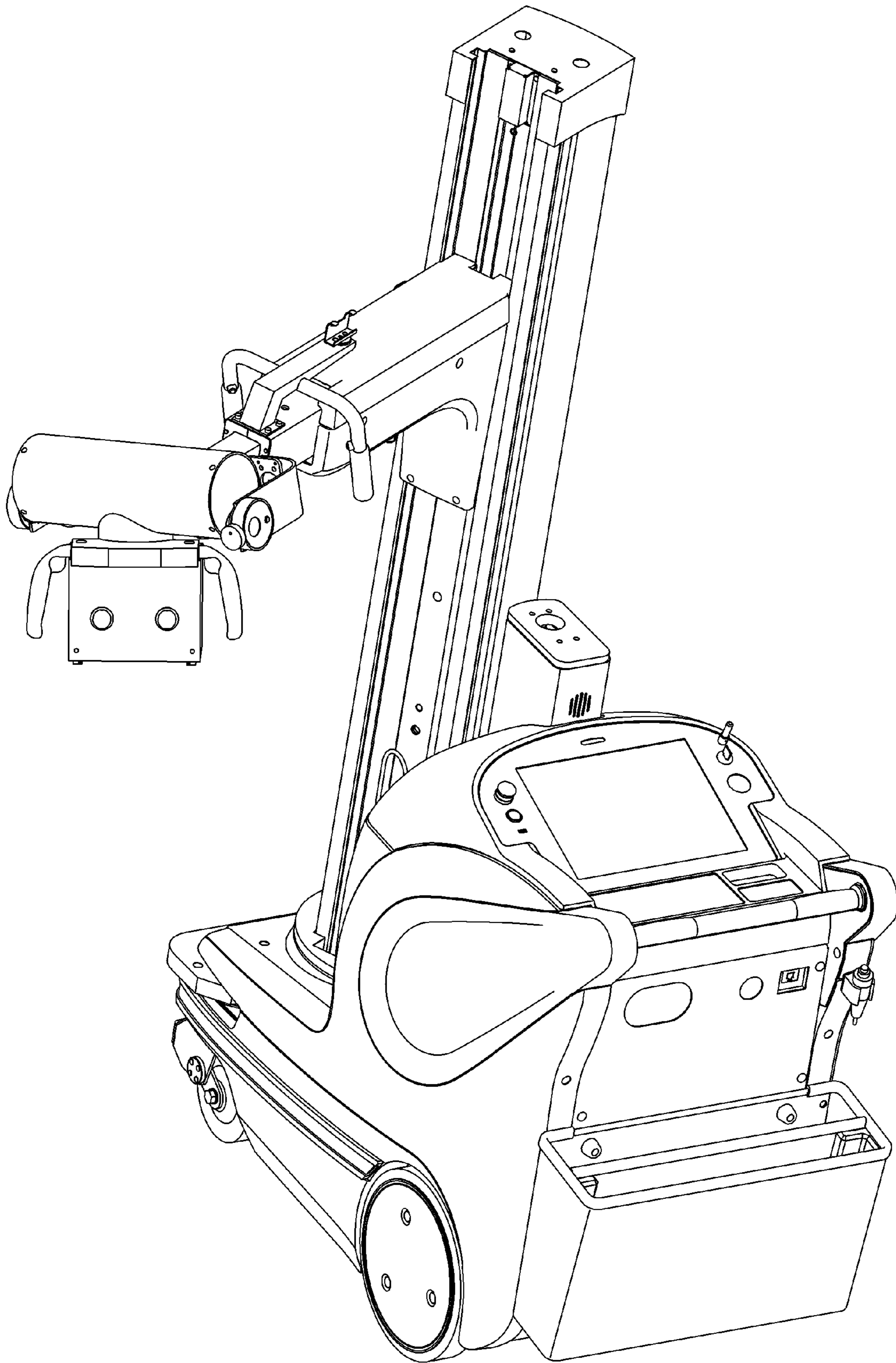


FIG. 16

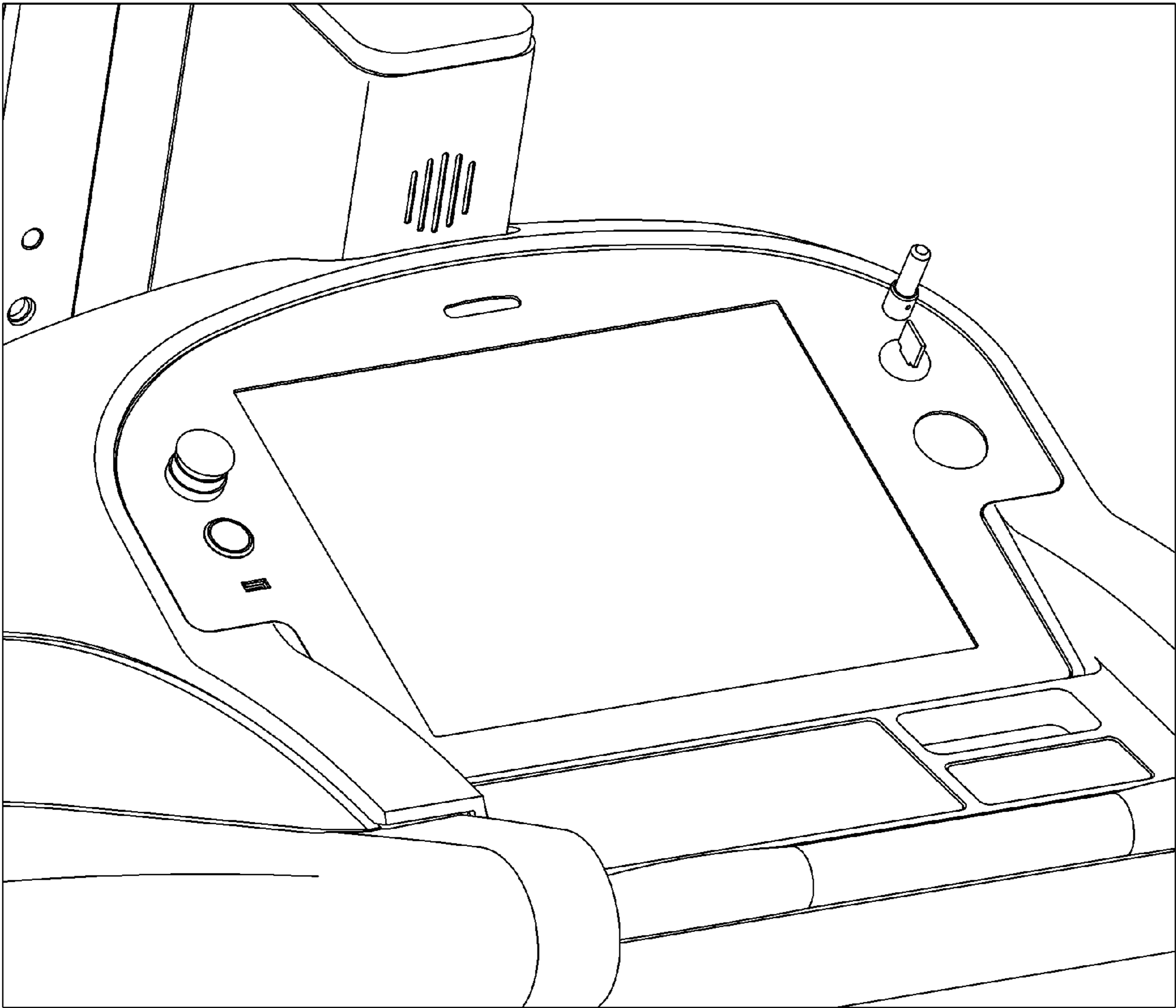


FIG. 17